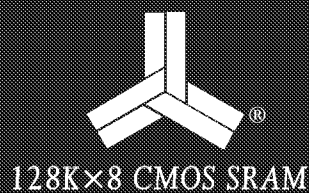


High Performance 128K×8 CMOS SRAM

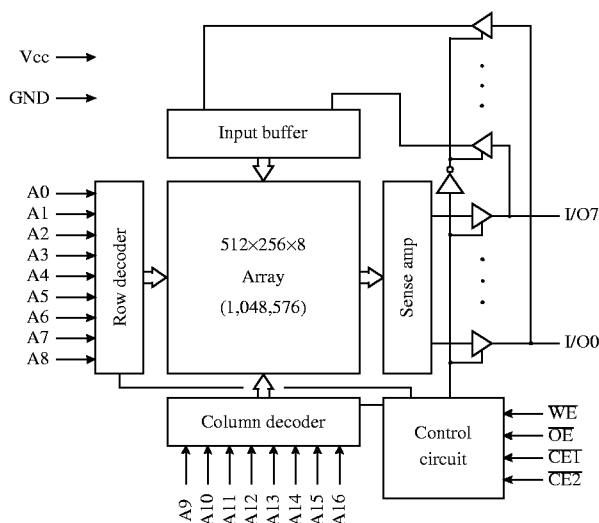


AS7C1024
AS7C31024

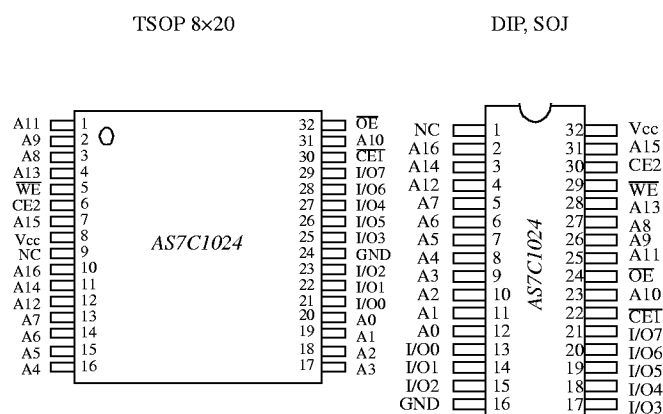
Features

- Organization: 131,072 words × 8 bits
- High speed
 - 10/12/15/20 ns address access time
 - 3/3/4/5 ns output enable access time
- Low power consumption
 - Active: 660 mW max (15 ns cycle)
 - Standby: 55 mW max, CMOS I/O
 - Very low DC component in active power
- 2.0V data retention
- Equal access and cycle times
- Easy memory expansion with $\overline{\text{CET}}$, CE2, $\overline{\text{OE}}$ inputs
- TTL/LVTTL-compatible, three-state I/O
- 32-pin JEDEC standard packages
 - 300 mil PDIP and SOJ
 - Socket compatible with 7C512 (64K×8)
 - 400 mil PDIP and SOJ
 - 8×20 TSOP
- ESD protection ≥ 2000 volts
- Latch-up current ≥ 200 mA
- 3.3V and 5.0V versions available
- Industrial and commercial temperature available

Logic block diagram



Pin arrangement



Selection guide

		7C1024-10	7C1024-12	7C1024-15	7C1024-20	
		—	7C31024-12	7C31024-15	7C31024-20	Unit
Maximum address access time		10	12	15	20	ns
Maximum output enable access time		3	3	4	5	ns
Maximum operating current	AS7C1024	175	160	120	110	mA
	AS7C31024	—	100	70	65	mA
Maximum CMOS standby current		10.0	10.0	10.0	10.0	mA

Shaded areas contain advance information.

AS7C1024 AS7C31024



Functional description

The AS7C1024 and AS7C31024 are high performance CMOS 1,048,576-bit Static Random Access Memories (SRAM) organized as 131,072 words \times 8 bits. It is designed for memory applications where fast data access, low power, and simple interfacing are desired.

Equal address access and cycle times (t_{AA} , t_{RC} , t_{WC}) of 10/12/15/20 ns with output enable access times (t_{OE}) of 3/3/4/5 ns are ideal for high performance applications. Active high and low chip enables ($\overline{CE1}$, $CE2$) permit easy memory expansion with multiple-bank memory systems.

When $\overline{CE1}$ is HIGH or $CE2$ is LOW the device enters standby mode. The standard AS7C1024 is guaranteed not to exceed 55 mW power consumption in standby mode. Both devices offer 2.0V data retention.

A write cycle is accomplished by asserting write enable (\overline{WE}) and both chip enables ($\overline{CE1}$, $CE2$). Data on the input pins I/O0-I/O7 is written on the rising edge of \overline{WE} (write cycle 1) or the active-to-inactive edge of $\overline{CE1}$ or $CE2$ (write cycle 2). To avoid bus contention, external devices should drive I/O pins only after outputs have been disabled with output enable (\overline{OE}) or write enable (\overline{WE}).

A read cycle is accomplished by asserting output enable (\overline{OE}) and both chip enables ($\overline{CE1}$, $CE2$), with write enable (\overline{WE}) HIGH. The chip drives I/O pins with the data word referenced by the input address. When either chip enable or output enable is inactive, or write enable is active, output drivers stay in high-impedance mode.

All chip inputs and outputs are TTL/LVTTL-compatible, and operation is from a single 5V supply (AS7C1024) or 3.3V supply (AS7C31024). The AS7C1024 and AS7C31024 are packaged in common industry standard packages.

Absolute maximum ratings

Parameter	Symbol	Min	Max	Unit
Voltage on any pin relative to GND	V_t	-0.5	+7.0	V
Power dissipation	P_D	—	1.0	W
Storage temperature (plastic)	T_{stg}	-55	+150	°C
Temperature under bias	T_{bias}	-10	+85	°C
DC output current	I_{out}	—	20	mA

Stresses greater than those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions outside those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

Truth table

$\overline{CE1}$	$CE2$	\overline{WE}	\overline{OE}	Data	Mode
H	X	X	X	High Z	Standby (I_{SB} , I_{SB1})
X	L	X	X	High Z	Standby (I_{SB} , I_{SB1})
L	H	H	H	High Z	Output disable
L	H	H	L	D_{out}	Read
L	H	L	X	D_{in}	Write

Key: X = Don't Care, L = LOW, H = HIGH

Recommended operating conditions

Parameter		Symbol	Min	Nominal	Max	Unit
Supply voltage	AS7C1024	V_{CC}	4.5	5.0	5.5	V
	AS7C31024	V_{CC}	3.0	3.3	3.6	V
		GND	0.0	0.0	0.0	V
Input voltage	AS7C1024	V_{IH}	2.2	—	$V_{CC} + 0.5$	V
	AS7C31024	V_{IH}	2.0	—	$V_{CC} + 0.5$	V
		V_{IL}	-0.5	—	0.8	V

[†] V_{IL} min = -3.0V for pulse width less than $t_{RC}/2$.



DC operating characteristics ¹

Parameter	Symbol	Test conditions	-10		-12		-15		-20		Unit	
			Min	Max	Min	Max	Min	Max	Min	Max		
Input leakage current	I _{LI}	V _{CC} = Max, V _{in} = GND to V _{CC}	—	1	—	1	—	1	—	1	μA	
Output leakage current	I _{LO}	CET = V _{IH} or CE2 = V _{IL} , V _{CC} = Max, V _{out} = GND to V _{CC}	—	1	—	1	—	1	—	1	μA	
Operating power supply current	I _{CC}	CET = V _{IL} , CE2 = V _{IH} , f = f _{max} , I _{out} = 0 mA	AS7C1024	—	175	—	160	—	120	—	110	mA
			AS7C31024	—	—	—	100	—	70	—	65	mA
Standby power supply current	I _{SB}	CET = V _{IH} or CE2 = V _{IL} , f = f _{max}	—	55	—	50	—	40	—	40	mA	
	I _{SB1}	CET ≥ V _{CC} –0.2V or CE2 ≤ 0.2V, V _{in} ≤ 0.2V or V _{in} ≥ V _{CC} –0.2V, f = 0	—	10	—	10	—	10	—	10	mA	
Output voltage	V _{OL}	I _{OL} = 8 mA, V _{CC} = Min	—	0.4	—	0.4	—	0.4	—	0.4	V	
	V _{OH}	I _{OH} = –4 mA, V _{CC} = Min	2.4	—	2.4	—	2.4	—	2.4	—	V	

Shaded areas contain advance information.

Capacitance ²

($f = 1 \text{ MHz}, T_a = \text{Room temperature}, V_{CC} = 5\text{V}$)

Parameter	Symbol	Signals	Test conditions	Max	Unit
Input capacitance	C_{IN}	A, $\overline{\text{CET}}$, CE2, $\overline{\text{WE}}$, $\overline{\text{OE}}$	$V_{in} = 0\text{V}$	5	pF
I/O capacitance	$C_{I/O}$	I/O	$V_{in} = V_{out} = 0\text{V}$	7	pF

Read cycle ^{3,9,12}

Parameter	Symbol	-10		-12		-15		-20		Unit	Notes
		Min	Max	Min	Max	Min	Max	Min	Max		
Read cycle time	t_{RC}	10	—	12	—	15	—	20	—	ns	
Address access time	t_{AA}	—	10	—	12	—	15	—	20	ns	3
Chip enable ($\overline{\text{CET}}$) access time	t_{ACE1}	—	10	—	12	—	15	—	20	ns	3, 12
Chip enable (CE2) access time	t_{ACE2}	—	10	—	12	—	15	—	20	ns	3, 12
Output enable ($\overline{\text{OE}}$) access time	t_{OE}	—	3	—	3	—	4	—	5	ns	
Output hold from address change	t_{OH}	2	—	3	—	3	—	3	—	ns	5
$\overline{\text{CET}}$ LOW to output in Low Z	t_{CLZ1}	3	—	3	—	3	—	3	—	ns	4, 5, 12
CE2 HIGH to output in Low Z	t_{CLZ2}	3	—	3	—	3	—	3	—	ns	4, 5, 12
$\overline{\text{CET}}$ HIGH to output in High Z	t_{CHZ1}	—	3	—	3	—	4	—	5	ns	4, 5, 12
CE2 LOW to output in High Z	t_{CHZ2}	—	3	—	3	—	4	—	5	ns	4, 5, 12
$\overline{\text{OE}}$ LOW to output in Low Z	t_{OLZ}	0	—	0	—	0	—	0	—	ns	4, 5
$\overline{\text{OE}}$ HIGH to output in High Z	t_{OHZ}	—	3	—	3	—	4	—	5	ns	4, 5
Power up time	t_{PU}	0	—	0	—	0	—	0	—	ns	4, 5, 12
Power down time	t_{PD}	—	10	—	12	—	15	—	20	ns	4, 5, 12

AS7C1024 AS7C31024



Key to switching waveforms

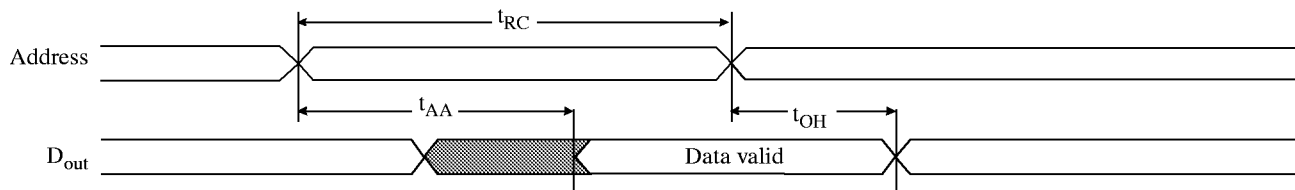
Rising input

Falling input

Undefined output/don't care

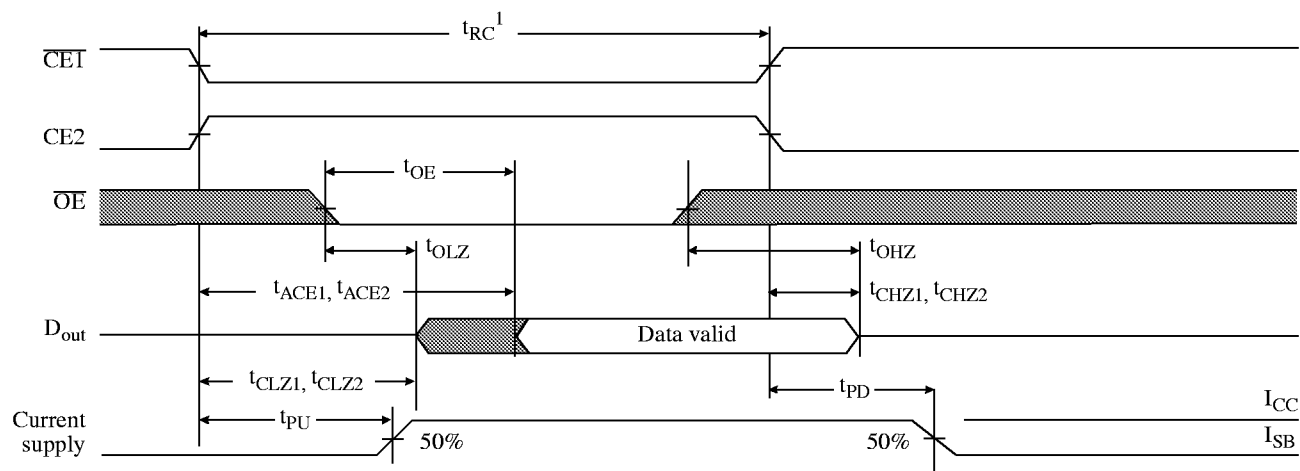
Read waveform 1 3,6,7,9,12

Address controlled



Read waveform 2 3,6,8,9,12

$\overline{\text{CE1}}$ and CE2 controlled



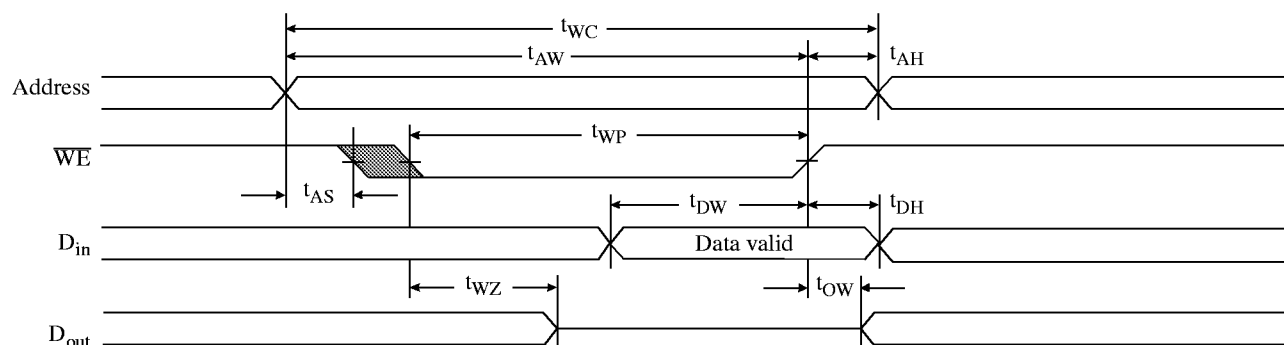
Write cycle 11, 12

Parameter	Symbol	-10		-12		-15		-20		Unit	Notes
		Min	Max	Min	Max	Min	Max	Min	Max		
Write cycle time	t_{WC}	10	—	12	—	15	—	20	—	ns	
Chip enable ($\overline{\text{CE1}}$) to write end	t_{CW1}	9	—	10	—	12	—	12	—	ns	12
Chip enable (CE2) to write end	t_{CW2}	9	—	10	—	12	—	12	—	ns	12
Address setup to write end	t_{AW}	9	—	10	—	12	—	12	—	ns	
Address setup time	t_{AS}	0	—	0	—	0	—	0	—	ns	12
Write pulse width	t_{WP}	7	—	8	—	9	—	12	—	ns	
Address hold from end of write	t_{AH}	0	—	0	—	0	—	0	—	ns	
Data valid to write end	t_{DW}	6	—	6	—	9	—	10	—	ns	
Data hold time	t_{DH}	0	—	0	—	0	—	0	—	ns	4, 5
Write enable to output in High Z	t_{WZ}	—	5	—	5	—	5	—	5	ns	4, 5
Output active from write end	t_{OW}	3	—	3	—	3	—	3	—	ns	4, 5

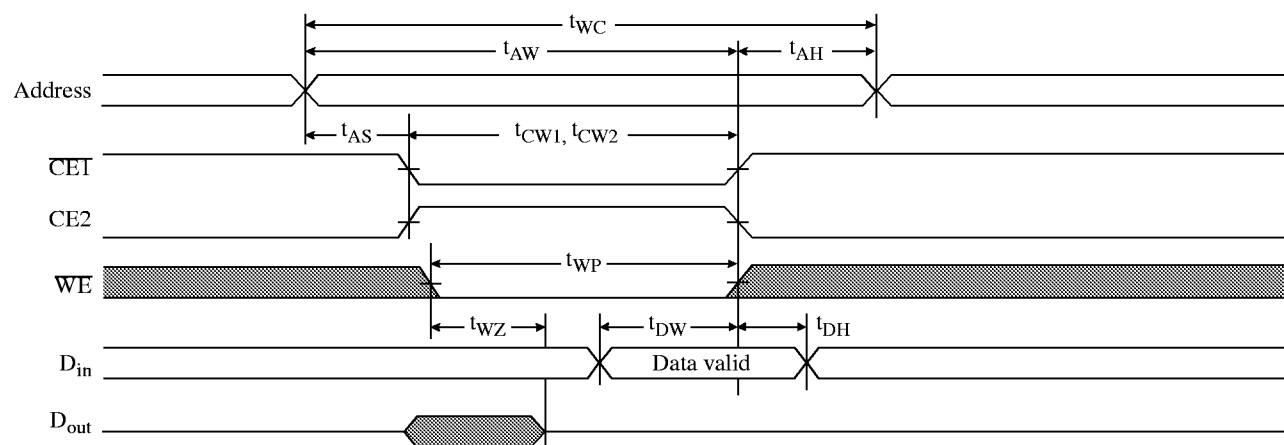
Shaded areas contain advance information.


Write waveform 1 ^{10,11,12}

WE controlled

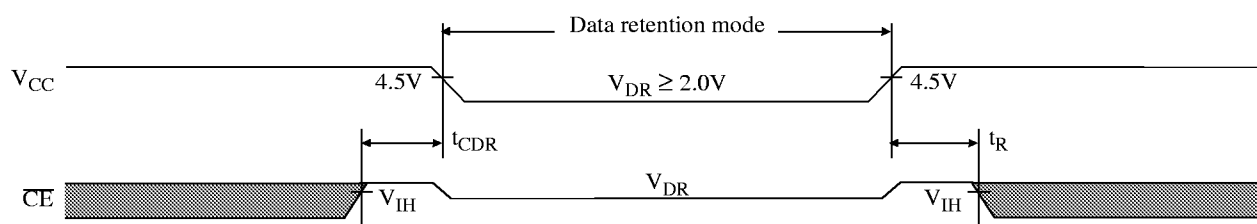

Write waveform 2 ^{10,11,12}

CE1 and CE2 controlled


Data retention characteristics ¹⁴

Parameter	Symbol	Test conditions	Min	Max	Unit
V_{CC} for data retention	V_{DR}	$V_{CC} = 2.0V$	2.0	—	V
Data retention current	I_{CCDR}	$\overline{CE1} \geq V_{CC} - 0.2V$ or $CE2 \leq 0.2V$	—	500	μA
Chip deselect to data retention time	t_{CDR}		0	—	ns
Operation recovery time	t_R	$V_{in} \geq V_{CC} - 0.2V$ or $V_{in} \leq 0.2V$	t_{RC}	—	ns
Input leakage current	$ I_{LI} $		—	1	μA

Data retention waveform





AC test conditions

- 5V output load: see Figure B, except as noted see Figure C.
- 3.3V output load: see Figure D, except as noted see Figure E.
- Input pulse level: GND to 3.0V. See Figure A.
- Input rise and fall times: 5 ns. See Figure A.
- Input and output timing reference levels: 1.5V.

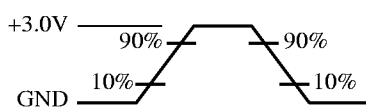


Figure A: Input waveform

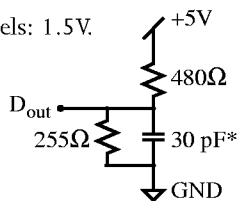


Figure B: Output load

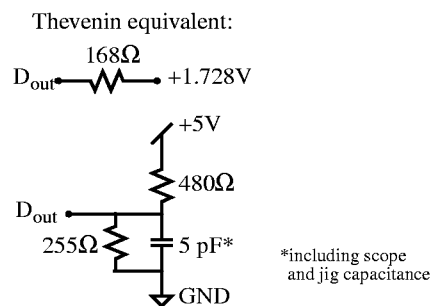


Figure C: Output load for t_{CLZ} , t_{CHZ} , t_{OLZ} , t_{OHZ} , t_{OW}

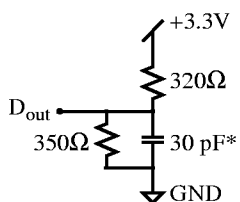


Figure D: Output load

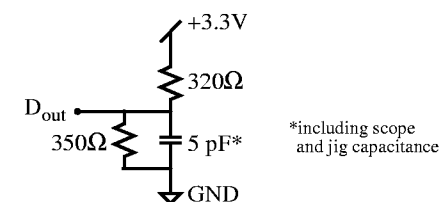


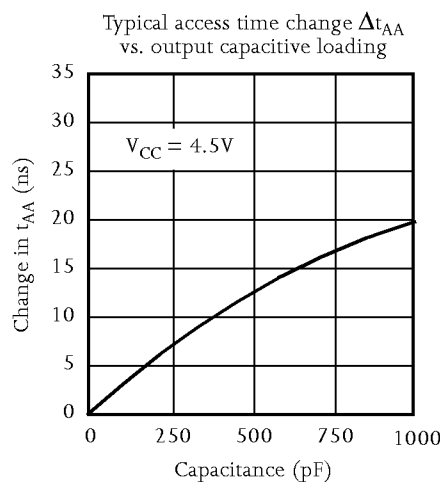
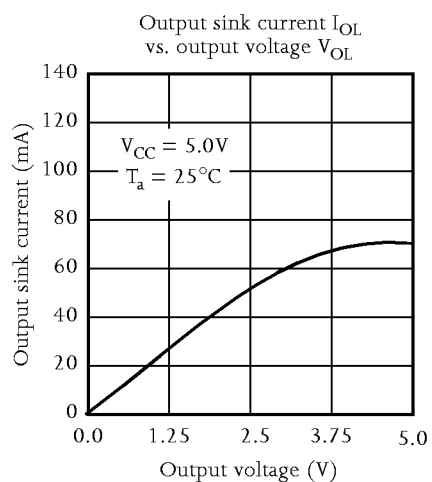
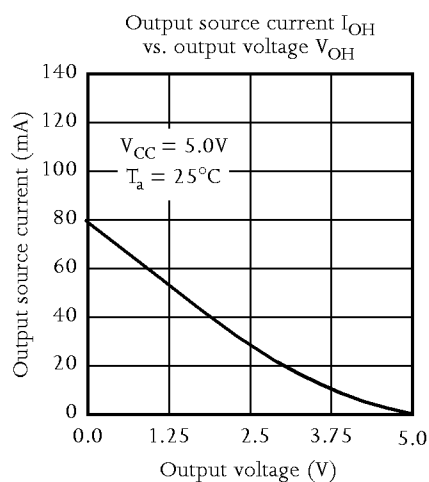
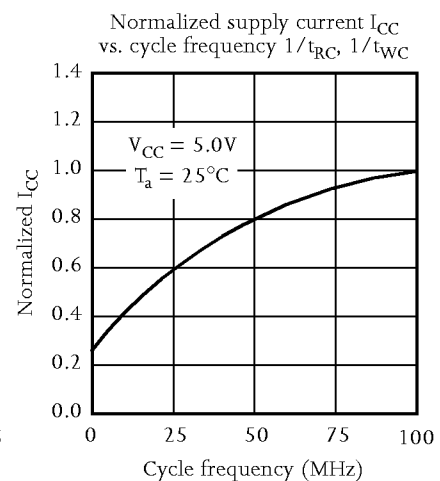
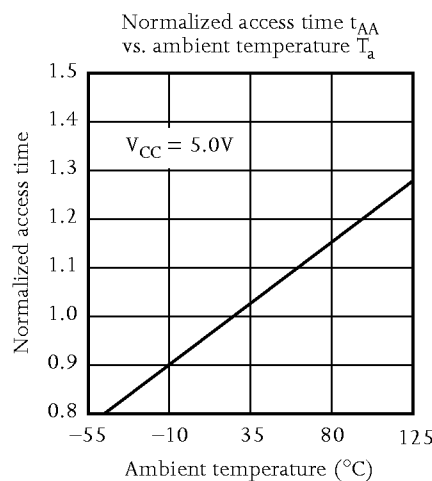
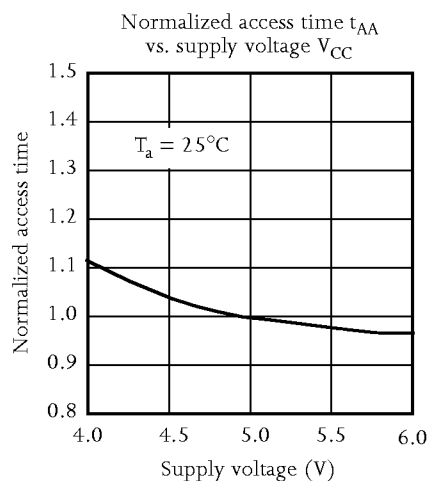
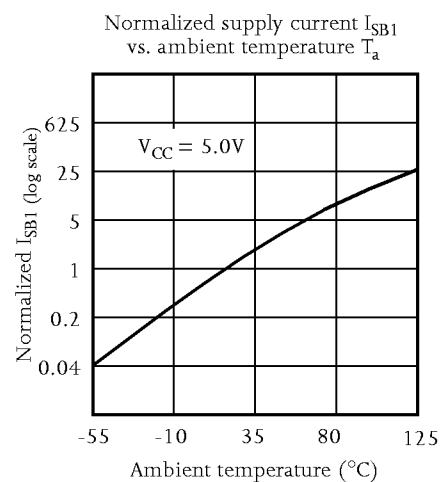
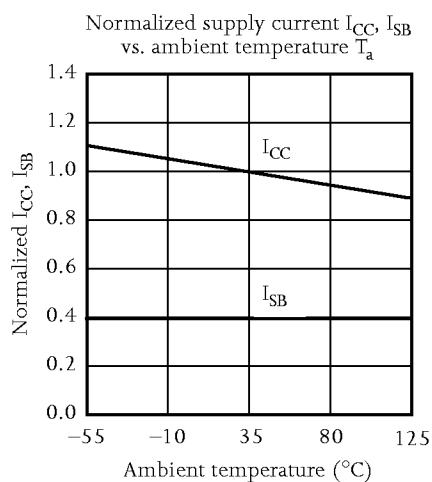
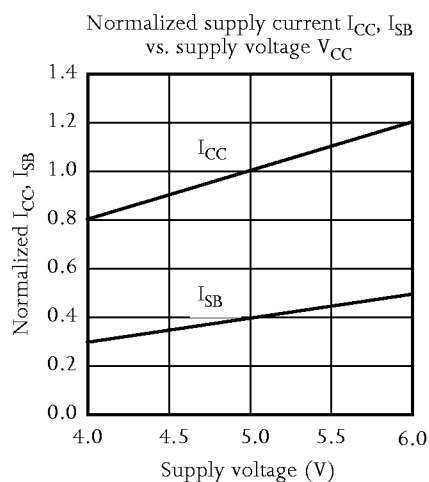
Figure C: Output load for t_{CLZ} , t_{CHZ} , t_{OLZ} , t_{OHZ} , t_{OW}

Notes

- 1 During V_{CC} power-up, a pull-up resistor to V_{CC} on \overline{CET} is required to meet I_{SB} specification.
- 2 This parameter is sampled and not 100% tested.
- 3 For test conditions, see AC Test Conditions, Figures A, B, C.
- 4 t_{CLZ} and t_{CHZ} are specified with $CL = 5pF$ as in Figure C. Transition is measured $\pm 500mV$ from steady-state voltage.
- 5 This parameter is guaranteed but not tested.
- 6 \overline{WE} is HIGH for read cycle.
- 7 \overline{CET} and \overline{OE} are LOW and $CE2$ is HIGH for read cycle.
- 8 Address valid prior to or coincident with \overline{CE} transition LOW.
- 9 All read cycle timings are referenced from the last valid address to the first transitioning address.
- 10 \overline{CET} or \overline{WE} must be HIGH or $CE2$ LOW during address transitions.
- 11 All write cycle timings are referenced from the last valid address to the first transitioning address.
- 12 \overline{CET} and $CE2$ have identical timing.
- 13 This data applicable to the AS7C1024. The AS7C31024 functions similarly.
- 14 2V data retention applies to commercial temperature operating range only.



Typical DC and AC characteristics



AS7C1024 AS7C31024



AS7C1024 ordering codes

Package \ Access time	10 ns	12 ns	15 ns	20 ns
Plastic DIP, 300 mil		AS7C1024-12TPC	AS7C1024-15TPC	AS7C1024-20TPC
		AS7C31024-12TPC	AS7C31024-15TPC	AS7C31024-20TPC
Plastic DIP, 400 mil		AS7C1024-12PC	AS7C1024-15PC	AS7C1024-20PC
		AS7C31024-12PC	AS7C31024-15PC	AS7C31024-20PC
Plastic SOJ, 300 mil	AS7C1024-10TJC	AS7C1024-12TJC	AS7C1024-15TJC	AS7C1024-20TJC
		AS7C31024-12TJC	AS7C31024-15TJC	AS7C31024-20TJC
			AS7C31024-15TJI	AS7C31024-20TJI
Plastic SOJ, 400 mil	AS7C1024-10JC	AS7C1024-12JC	AS7C1024-15JC	AS7C1024-20JC
		AS7C31024-12JC	AS7C1024-15JI	AS7C1024-20JI
			AS7C31024-15JC	AS7C31024-20JC
			AS7C31024-15JI	AS7C31024-20JI
TSOP 8×20		AS7C1024-12TC	AS7C1024-15TC	AS7C1024-20TC
		AS7C31024-12TC	AS7C31024-15TC	AS7C31024-20TC

Shaded areas contain advance information.

AS7C1024 part numbering system

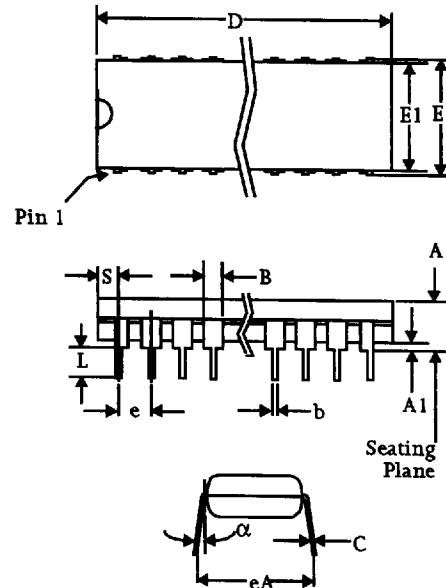
AS7C	X	1024	--XX	X	X
SRAM prefix	Blank 3	= 5V CMOS = 3.3V CMOS	Device number	Access time	Package: TP = PDIP 300 mil P = PDIP 400 mil TJ = SOJ 300 mil J = SOJ 400 mil T = TSOP 8×20
					C = Commercial temperature range, 0°C to 70 °C I = Industrial temperature range, -40°C to 85°C



Plastic dual in-line package (PDIP)

	20-pin 300 mil		28-pin 300 mil		32-pin 300 mil		32-pin 400 mil	
	Min	Max	Min	Max	Min	Max	Min	Max
A	-	0.175	-	0.175	-	0.180	-	0.200
A1	0.010	-	0.010	-	0.015	-	0.015	-
B	0.046	0.054	0.058	0.064	0.045	0.055	0.045	0.065
b	0.018	0.024	0.016	0.022	0.015	0.021	0.014	0.022
C	0.008	0.014	0.008	0.014	0.008	0.012	0.009	0.015
D	-	0.980	-	1.400	-	1.571	-	1.620
E	0.290	0.310	0.295	0.320	0.300	0.325	0.390	0.425
E1	0.263	0.293	0.278	0.298	0.280	0.295	0.340	0.390
e	0.100 BSC		0.100 BSC		0.100 BSC		0.100 BSC	
eA	0.310	0.350	0.330	0.370	0.330	0.370	0.430	0.470
L	0.110	0.130	0.120	0.140	0.110	0.142	0.118	0.162
α	0°	15°	0°	15°	0°	15°	0°	15°
S	-	0.040	-	0.055	-	0.043	-	0.065

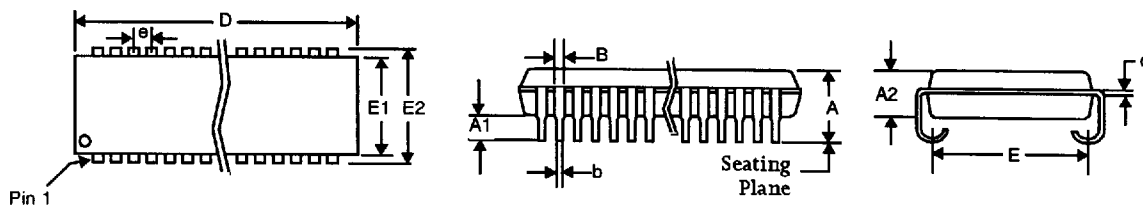
Dimensions in inches



Plastic small outline J-bend (SOJ)

	20/26-pin 300 mil		28-pin 300 mil		32-pin 300 mil		28-pin 400 mil		32-pin 400 mil		36-pin 400 mil		40-pin 400 mil		42-pin 400 mil		44-pin 400 mil	
	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max
A	-	0.140	-	0.140	-	0.145	0.132	0.146	-	0.145	-	-	-	0.145	0.128	0.148	0.128	0.148
A1	0.020	-	0.025	-	0.025	-	0.062	-	0.025	-	-	-	0.025	-	0.025	-	0.025	-
A2	0.095	0.105	0.095	0.105	0.086	0.105	0.105	115	0.086	0.115	0.102	NOM	0.086	0.115	1.105	1.115	1.105	1.115
B	0.025	0.032	0.028	TYP	0.026	0.032	0.024	0.032	0.026	0.032	-	0.032	0.026	0.032	0.026	0.032	0.026	0.032
b	0.016	0.022	0.018	TYP	0.014	0.020	0.013	0.021	0.015	0.020	0.013	0.021	0.015	0.022	0.015	0.020	0.015	0.020
c	0.008	0.014	0.010	TYP	0.006	0.013	0.005	0.012	0.007	0.013	-	-	0.007	0.014	0.007	0.013	0.007	0.013
D	-	0.686	-	0.730	0.820	0.830	0.720	0.729	0.820	0.830	0.920	0.930	1.015	1.035	1.070	1.080	1.120	1.130
E	0.327	0.347	0.327	0.347	0.330	0.340	0.430	0.440	0.435	0.445	0.350	0.390	0.435	0.445	0.370	NOM	0.370	NOM
E1	0.295	0.305	0.295	0.305	0.292	0.305	0.395	0.405	0.395	0.405	0.400	NOM	0.395	0.405	0.395	0.405	0.395	0.405
E2	0.245	0.285	0.245	0.285	0.250	0.275	0.354	0.378	0.360	0.380	0.435	0.445	0.348	0.390	0.435	0.445	0.435	0.445
e	0.050 BSC		0.050 BSC		0.050 BSC		0.050 BSC		0.050 BSC		0.045	0.055	0.050 BSC		0.050 NOM		0.050 NOM	

Dimensions in inches



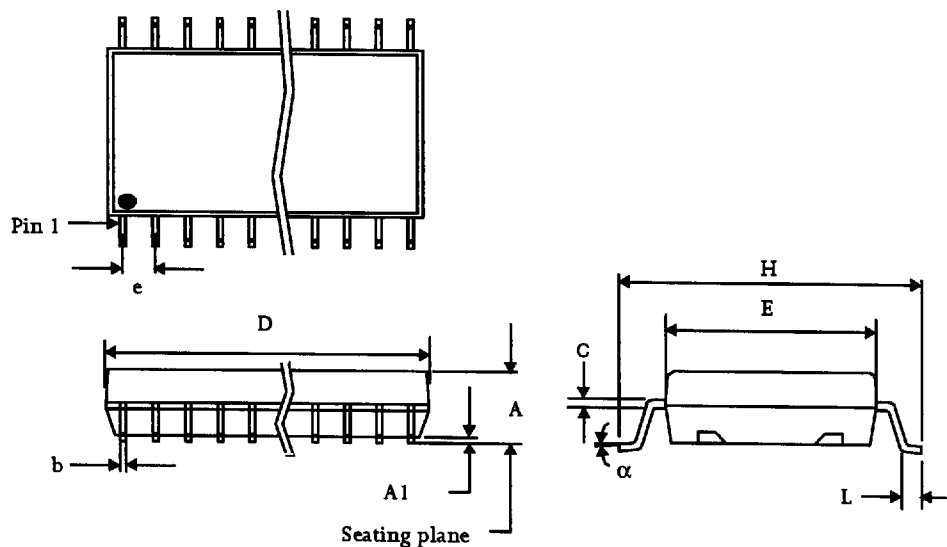
Package diagrams



Plastic small outline gull wing IC (SOIC)

28-pin 330 mil		
	Min	Max
A	-	0.112
A1	0.004	-
b	0.014	0.020
C	0.008	0.014
D	-	0.733
e	0.050 nominal	
E	0.326	0.336
H	0.453	0.477
L	0.028	0.044
α	0°	10°

Dimensions in inches



Thin small outline package (TSOP-I)

	28-pin 8×13.4		32-pin 8×20		40-pin 10×20	
	Min	Max	Min	Max	Min	Max
A	-	1.20	-	1.20	-	1.20
A1	0.05	0.15	0.05	0.15	0.05	0.15
A2	0.90	1.05	0.90	1.05	0.95	1.05
b	0.17	0.27	0.17	0.23	0.17	0.27
C	0.10	-	0.10	-	0.10	0.20
D	11.70	11.90	18.20	18.60	18.30	18.50
e	0.55 nominal		0.50 nominal		0.50 nominal	
E	8.0 nominal		7.80	8.20	9.90	10.10
Hd	13.20	13.60	19.80	20.20	19.80	20.20
L	0.30	0.70	0.40	0.60	0.50	0.70
α	0°	5°	1°	5°	0°	5°

Dimensions in millimeters

